



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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Product Summary

BV _{DSS}	R _{DS(ON)} Max	I _D T _C = +25°C
80V	3.9mΩ @ V _{GS} = 10V	100A
	6mΩ @ V _{GS} = 6V	82A

Features and Benefits

- 100% Unclamped Inductive Switching – Ensures More Reliable and Robust End Application
- Thermally Efficient Package – Cooler Running Applications
- High Conversion Efficiency
- Low R_{DS(ON)} – Minimizes On-State Losses

Description and Applications

This MOSFET is designed to minimize the on-state resistance (R_{DS(ON)}) yet maintain superior switching performance, making it ideal for high-efficiency power-management applications.

- Switching
- Synchronous rectification
- DC-DC converters

Mechanical Data

- Package: PowerDI[®]5060-8
- Package Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish – Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 (E3)
- Weight: 0.097 grams (Approximate)

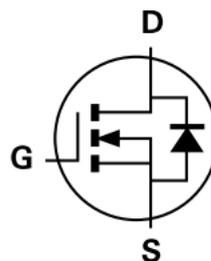
PowerDI5060-8/SWP (Type UX)



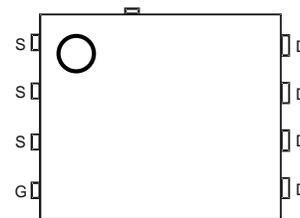
Top View



Bottom View



Internal Schematic



Top View
Pin Configuration

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	80	V
Gate-Source Voltage	V _{GSS}	±20	V
Continuous Drain Current, V _{GS} = 10V (Note 5)	I _D	T _C = +25°C 80	A
		T _C = +70°C	
Pulsed Drain Current (10μs Pulse, Duty Cycle = 1%)	I _{DM}	400	A
Continuous Body Diode Forward Current (Note 5)	I _S	100	A
Pulsed Body Diode Forward Current (10μs Pulse, Duty Cycle = 1%)	I _{SM}	400	A
Avalanche Current, L = 3mH (Note 6)	I _{AS}	15.8	A
Avalanche Energy, L = 3mH (Note 6)	E _{AS}	375.4	mJ
Avalanche Current, L = 0.1mH	I _{AS}	65	A
Avalanche Energy, L = 0.1mH	E _{AS}	211.4	mJ

Thermal Characteristics

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 7)	P _D	3.1	W
Thermal Resistance, Junction to Ambient (Note 7)	R _{θJA}	40	°C/W
Total Power Dissipation (Note 5)	P _D	83	W
Thermal Resistance, Junction to Case (Note 5)	R _{θJC}	1.5	°C/W
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C

- Notes:
5. Thermal resistance from junction to soldering point (on the exposed drain pad).
 6. Guaranteed by design. Not subject to product testing.
 7. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

Electrical Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	80	—	—	V	$V_{GS} = 0V, I_D = 1mA$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	1	μA	$V_{DS} = 64V, V_{GS} = 0V$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(TH)}$	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	2.5	3.9	m Ω	$V_{GS} = 10V, I_D = 30A$
		—	2.7	6		$V_{GS} = 6V, I_D = 30A$
Diode Forward Voltage	V_{SD}	—	0.8	1.3	V	$V_{GS} = 0V, I_S = 30A$
DYNAMIC CHARACTERISTICS (Note 6)						
Input Capacitance	C_{iss}	—	9081	—	pF	$V_{DS} = 40V, V_{GS} = 0V$ $f = 1MHz$
Output Capacitance	C_{oss}	—	556	—		
Reverse Transfer Capacitance	C_{rss}	—	80	—		
Gate Resistance	R_G	—	0.8	—	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$
Total Gate Charge	Q_g	—	136	—	nC	$V_{DS} = 40V, I_D = 30A, V_{GS} = 10V$
Gate-Source Charge	Q_{gs}	—	41	—		
Gate-Drain Charge	Q_{gd}	—	32	—		
Turn-On Delay Time	$t_{D(ON)}$	—	19	—	ns	$V_{DD} = 40V, V_{GS} = 10V$ $I_D = 30A, R_G = 2.5\Omega$
Turn-On Rise Time	t_r	—	31	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	63	—		
Turn-Off Fall Time	t_f	—	27	—		
Reverse-Recovery Time	t_{RR}	—	58	—	ns	$I_F = 30A, di/dt = 100A/\mu s$
Reverse-Recovery Charge	Q_{RR}	—	114	—	nC	

Note: 8. Short duration pulse test used to minimize self-heating effect.

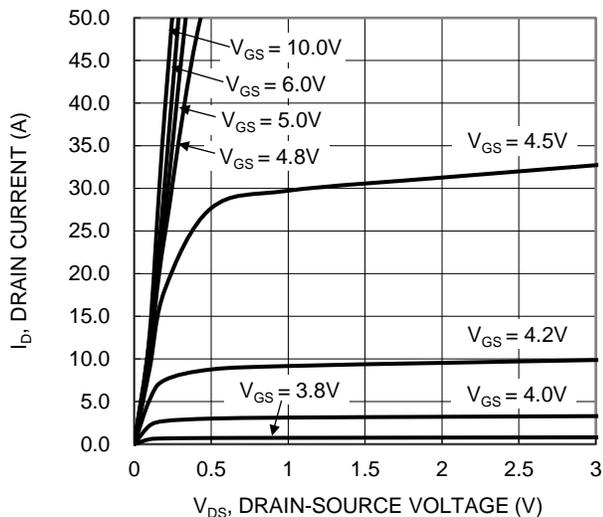


Figure 1. Typical Output Characteristic

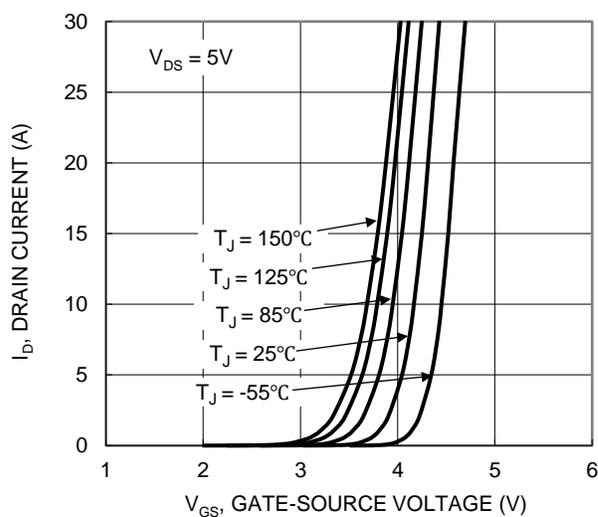


Figure 2. Typical Transfer Characteristic

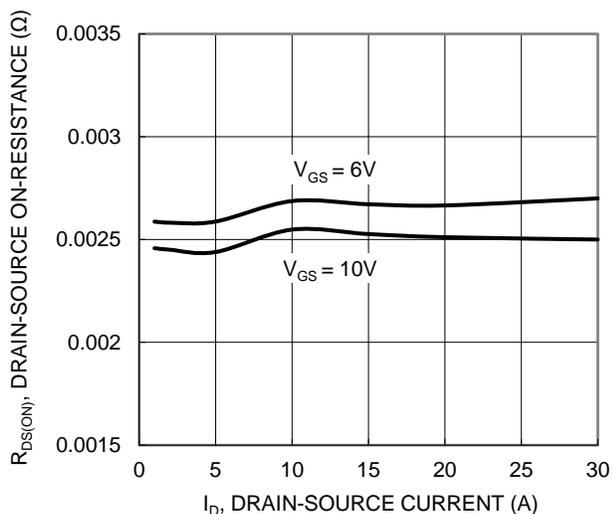


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

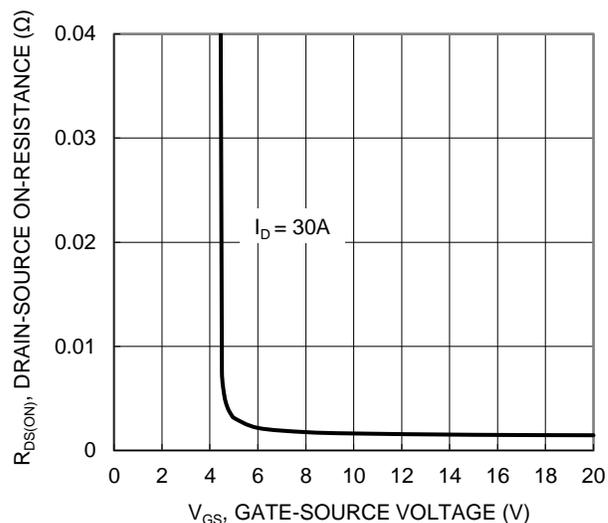


Figure 4. Typical Transfer Characteristic

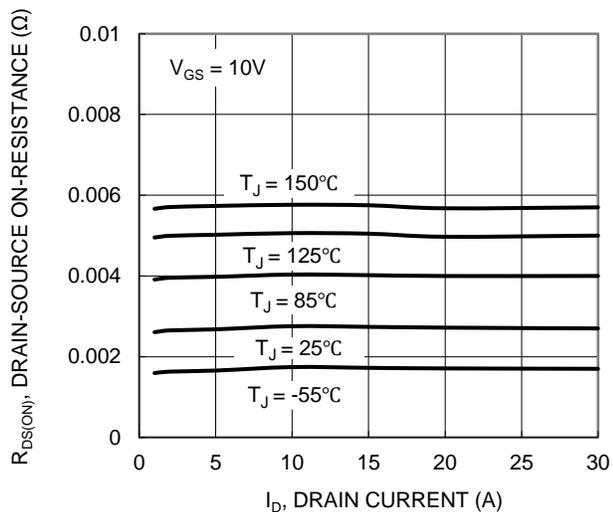


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

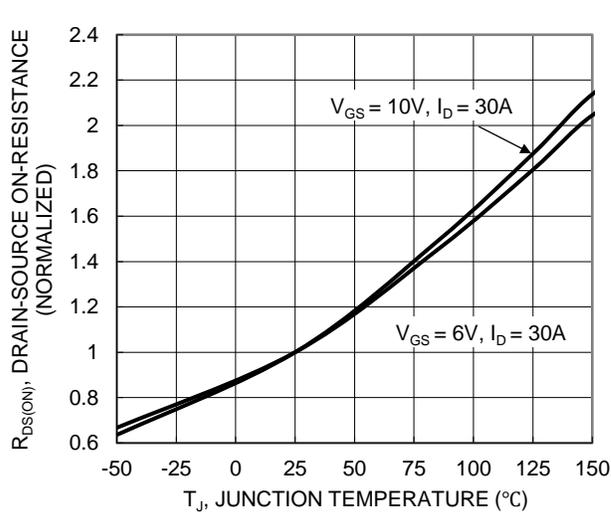


Figure 6. On-Resistance Variation with Junction Temperature

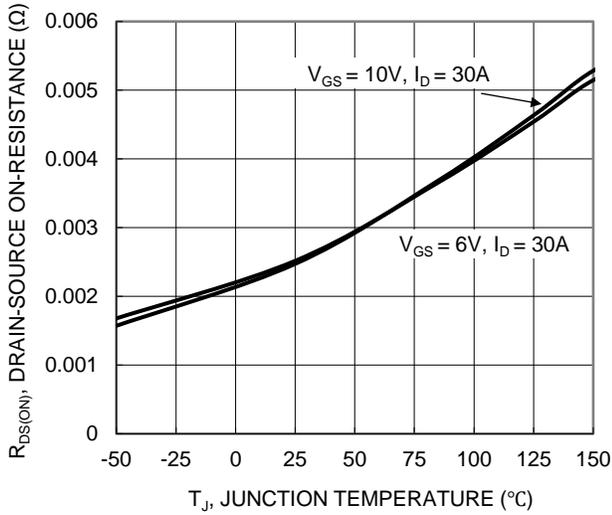


Figure 7. On-Resistance Variation with Junction Temperature

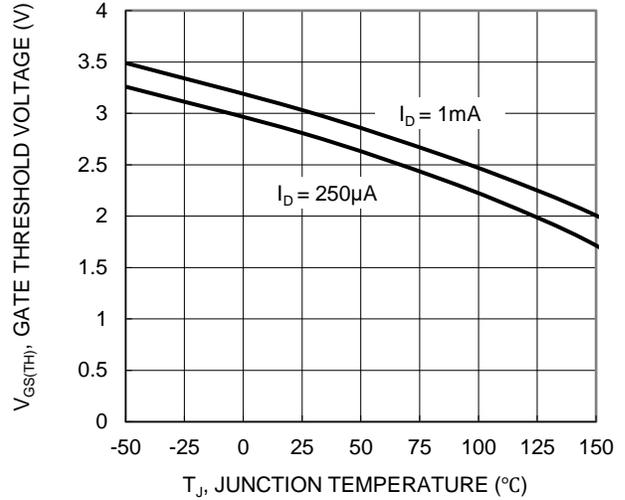


Figure 8. Gate Threshold Variation vs. Junction Temperature

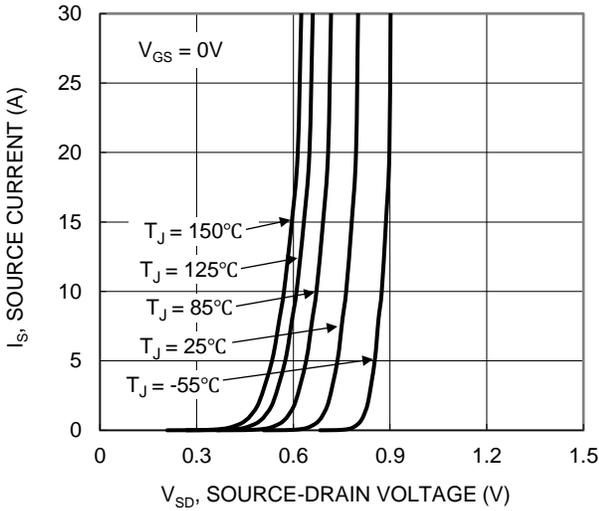


Figure 9. Diode Forward Voltage vs. Current

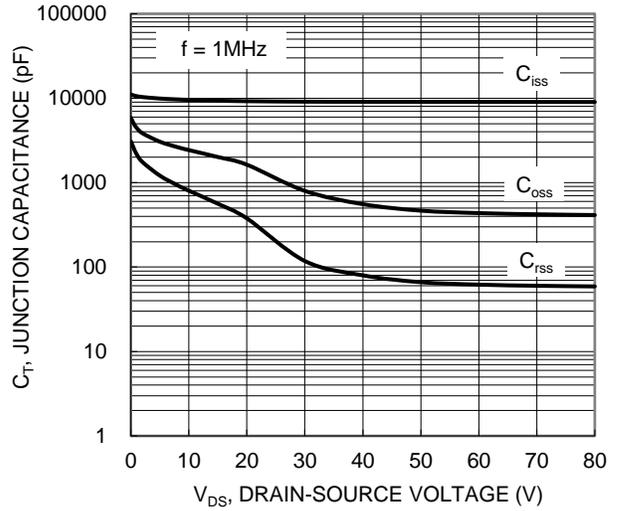


Figure 10. Typical Junction Capacitance

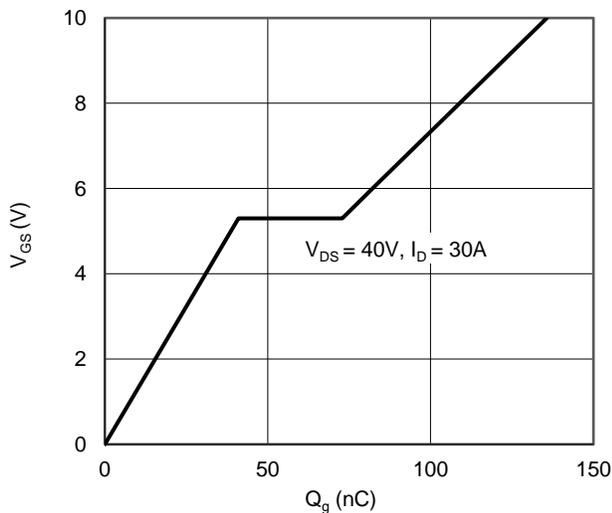


Figure 11. Gate Charge

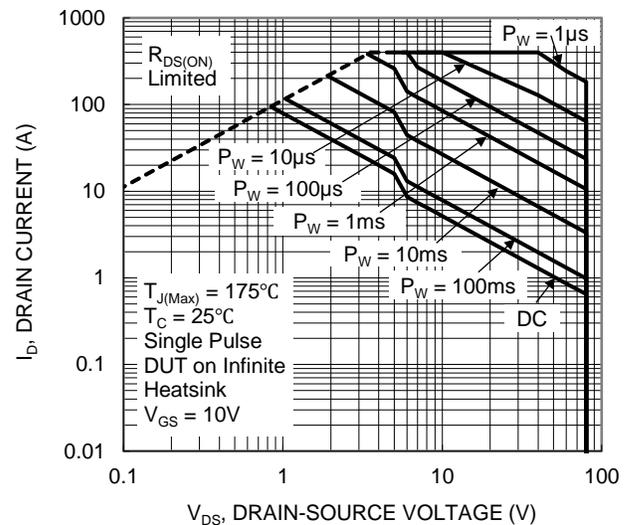


Figure 12. SOA, Safe Operation Area

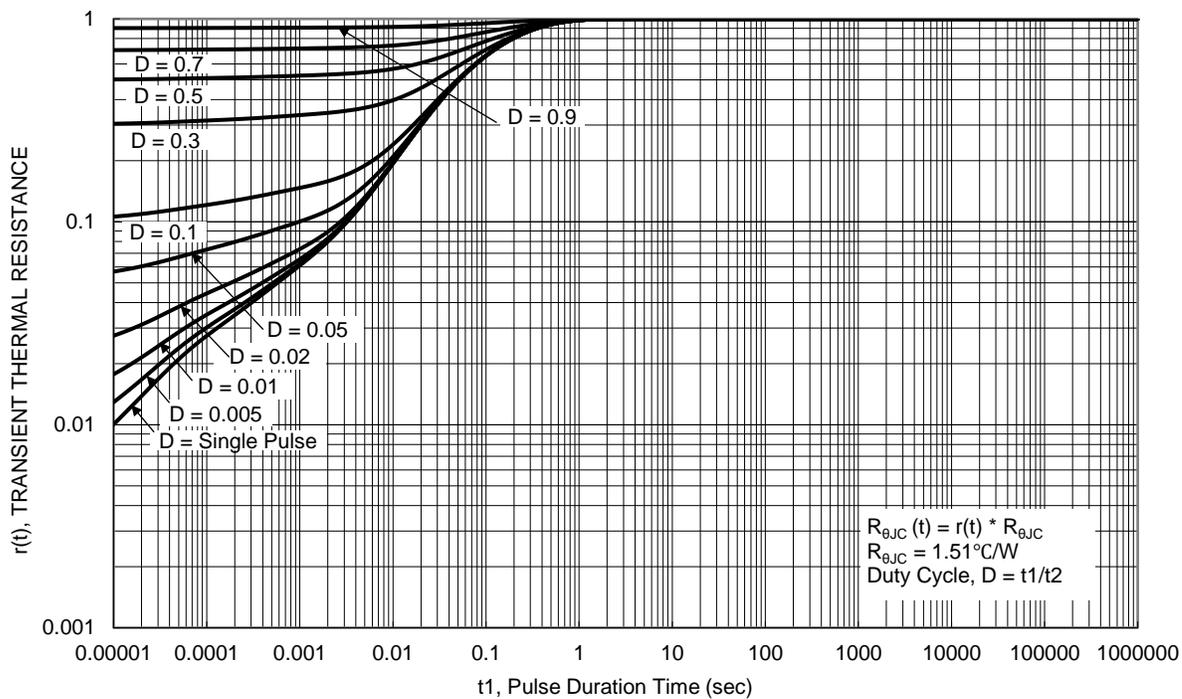


Figure 13. Transient Thermal Resistance

